

CORRIGENDUM

CORRIGENDUM/ ADDENDUM TO NIT FOR “SUPPLY, INSTALLATION & COMMISSIONING OF ATOMIC FORCE MICROSCOPE (AFM) WITH CONFOCAL RAMAN SPECTROMETER”

The detail of amendments made to the tender documents of “Supply, Installation & Commissioning of Atomic Force Microscope (AFM) with Confocal Raman Spectrometer” issued vide Tender No: IUAC/NIT/57/IS/2019-20 dated 14.02.2020 are described below. These amendments shall be read in continuation of Tender documents published on CPP portal and IUAC website. The details are as follows:

Sl.No.	Published as	Revised
1.	The Earnest Money Deposit (EMD) and tender fee shall be in the form of demand draft	The Earnest Money Deposit (EMD) and tender fee shall be in the form of demand draft/bank Guarantee/FDR
Under ATOMIC FORCE MICROSCOPE		
2	Pixel density 4000×4000 or more	Pixel density 1024×1024 or more
3	Piezo-driven scanner: one large ~ 90-100 μm and one small ~ 5-10μm	Piezo-driven scanner: ~ 90-100 μm
4	Active Vibration Isolation Platform; active range ~0.7-1000Hz, passive >1000Hz	Active Vibration Isolation Platform; active range ~0.7-1000Hz, passive >1000Hz and Optical table
Under RAMAN SPECTROMETER		
5	Calibration source: The system should be supplied with calibration sources for spectral calibration of spectrometer OR should have option for in-built calibration	Calibration source: The system should be supplied with in-built calibration
Under EXCITATION LASER FOR RAMAN SPECTROMETER		
6	The laser intensity of all lasers should be controllable to change the intensity from ~0 to 100% using neutral density filters or other mechanism with minimal of 16 steps or more.	The laser intensity of all lasers should be controllable to change the intensity from ~0 to 100% using neutral density filters or other mechanism with minimal of 9 steps or more.